

ADG1208/ADG1209

FEATURES

- <1 pC charge injection over full signal range
- 1 pF off capacitance
- 33 V supply range
- 120 Ω on resistance
- Fully specified at $\pm 15\text{ V}/+12\text{ V}$
- 3 V logic compatible inputs
- Rail-to-rail operation
- Break-before-make switching action
- Available in 16-lead TSSOP and 4 mm \times 4 mm LFCSP_VQ
- Typical power consumption < 0.03 μW

APPLICATIONS

- Audio and video routing
- Automatic test equipment
- Data-acquisition systems
- Battery-powered systems
- Sample-and-hold systems
- Communication systems

GENERAL DESCRIPTION

The ADG1208 and ADG1209 are monolithic, *iCMOS* analog multiplexers comprising eight single channels and four differential channels, respectively. The ADG1208 switches one of eight inputs to a common output as determined by the 3-bit binary address lines A0, A1, and A2. The ADG1209 switches one of four differential inputs to a common differential output as determined by the 2-bit binary address lines A0 and A1. An EN input on both devices is used to enable or disable the device. When disabled, all channels are switched off. When on, each channel conducts equally well in both directions and has an input signal range that extends to the supplies.

The *iCMOS* (industrial CMOS) modular manufacturing process combines high voltage CMOS (complementary metal-oxide semiconductor) and bipolar technologies. It enables the development of a wide range of high performance analog ICs capable of 33 V operation in a footprint that no other generation of high voltage parts has been able to achieve. Unlike analog ICs using conventional CMOS processes, *iCMOS* components can tolerate high supply voltages while providing increased performance, dramatically lower power consumption, and reduced package size.

FUNCTIONAL BLOCK DIAGRAMS

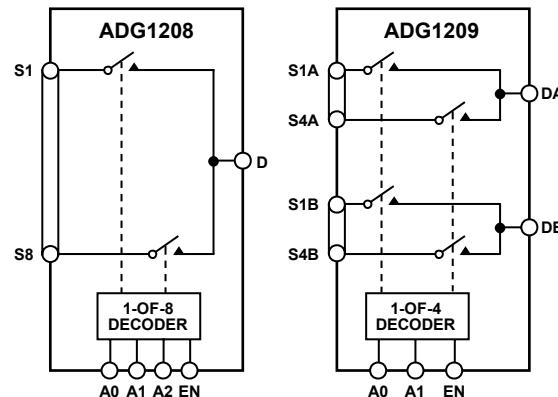
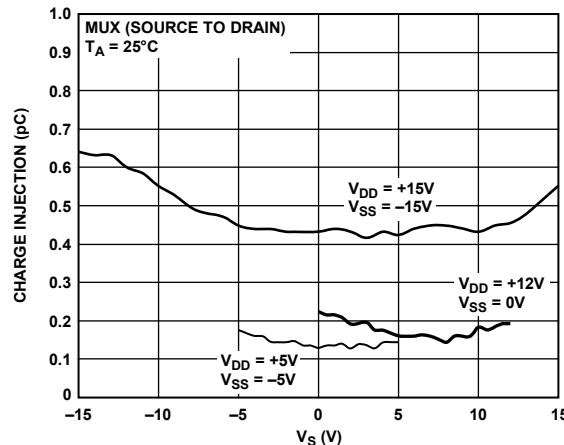


Figure 1.

05713-001

The ultralow capacitance and exceptionally low charge injection of these multiplexers make them ideal solutions for data acquisition and sample-and-hold applications, where low glitch and fast settling are required. Figure 2 shows that there is minimum charge injection over the entire signal range of the device. *iCMOS* construction also ensures ultralow power dissipation, making the parts ideally suited for portable and battery powered instruments.



05713-001

Figure 2. Source to Drain Charge Injection vs. Source Voltage

Rev. 0

Information furnished by Analog Devices is believed to be accurate and reliable. However, no responsibility is assumed by Analog Devices for its use, nor for any infringements of patents or other rights of third parties that may result from its use. Specifications subject to change without notice. No license is granted by implication or otherwise under any patent or patent rights of Analog Devices. Trademarks and registered trademarks are the property of their respective owners.

TABLE OF CONTENTS

Features	1	Absolute Maximum Ratings	7
Applications.....	1	ESD Caution.....	7
Functional Block Diagrams.....	1	Pin Configurations and Function Descriptions	8
General Description	1	Typical Performance Characteristics	10
Revision History	2	Terminology	14
Specifications.....	3	Test Circuits.....	15
Dual Supply	3	Outline Dimensions	17
Single Supply	5	Ordering Guide	17

REVISION HISTORY

4/06—Revision 0: Initial Version

SPECIFICATIONS

DUAL SUPPLY

$V_{DD} = +15 \text{ V} \pm 10\%$, $V_{SS} = -15 \text{ V} \pm 10\%$, $\text{GND} = 0 \text{ V}$, unless otherwise noted.¹

Table 1.

Parameter	+25°C	-40°C to +85°C	-40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range				V	
On Resistance, R_{ON}	120			Ω typ	$V_S = \pm 10 \text{ V}$, $I_S = -1 \text{ mA}$, see Figure 29
On Resistance Match Between Channels, ΔR_{ON}	200	240	270	Ω max	$V_{DD} = +13.5 \text{ V}$, $V_{SS} = -13.5 \text{ V}$
On Resistance Flatness, R_{FLAT} (On)	3.5			Ω typ	$V_S = \pm 10 \text{ V}$, $I_S = -1 \text{ mA}$
	6	10	12	Ω max	
	20			Ω typ	$V_S = -5 \text{ V}$, 0 V , $+5 \text{ V}$, $I_S = -1 \text{ mA}$
	64	76	83	Ω max	
LEAKAGE CURRENTS					
Source Off Leakage, I_S (Off)	± 0.02			nA typ	$V_D = \pm 10 \text{ V}$, $V_S = -10 \text{ V}$, see Figure 30
Drain Off Leakage, I_D (Off)	± 0.1	± 0.6	± 1	nA max	
ADG1208	± 0.02			nA typ	$V_S = 1 \text{ V}$, 10 V ; $V_D = 10 \text{ V}$, 1 V ; see Figure 30
ADG1209	± 0.1	± 0.6	± 1	nA max	
Channel On Leakage, I_D , I_S (On)	± 0.02			nA typ	$V_S = V_D = \pm 10 \text{ V}$, see Figure 31
ADG1208	± 0.2	± 0.6	± 1	nA max	
ADG1209	± 0.2	± 0.6	± 1	nA max	
DIGITAL INPUTS					
Input High Voltage, V_{INH}			2.0	V min	
Input Low Voltage, V_{INL}			0.8	V max	
Input Current, I_{INL} or I_{INH}	± 0.005		± 0.1	μA max	$V_{IN} = V_{INL}$ or V_{INH}
Digital Input Capacitance, C_{IN}	2			μA max	
				pF typ	
DYNAMIC CHARACTERISTICS ²					
Transition Time, $t_{TRANSITION}$	80			ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{ pF}$
	130	165	185	ns max	$V_S = 10 \text{ V}$, see Figure 32
t_{ON} (EN)	75			ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{ pF}$
	95	105	115	ns max	$V_S = 10 \text{ V}$, see Figure 34
t_{OFF} (EN)	83			ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{ pF}$
	100	125	140	ns max	$V_S = 10 \text{ V}$, see Figure 34
Break-Before-Make Time Delay, t_{BBM}	25		10	ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{ pF}$
				ns min	$V_{S1} = V_{S2} = 10 \text{ V}$, see Figure 33
Charge Injection	0.4			pC typ	$V_S = 0 \text{ V}$, $R_S = 0 \Omega$, $C_L = 1 \text{ nF}$, see Figure 35
Off Isolation	-85			dB typ	$R_L = 50 \Omega$, $C_L = 5 \text{ pF}$, $f = 1 \text{ MHz}$, see Figure 36
Channel-to-Channel Crosstalk	-85			dB typ	$R_L = 50 \Omega$, $C_L = 5 \text{ pF}$, $f = 1 \text{ MHz}$, see Figure 38
Total Harmonic Distortion + Noise	0.15			% typ	$R_L = 10 \text{ k}\Omega$, 5 V rms , $f = 20 \text{ Hz}$ to 20 kHz , see Figure 39
-3 dB Bandwidth	550			MHz typ	$R_L = 50 \Omega$, $C_L = 5 \text{ pF}$, see Figure 37
C_S (Off)	1			pF typ	$f = 1 \text{ MHz}$, $V_S = 0 \text{ V}$
	1.5			pF max	$f = 1 \text{ MHz}$, $V_S = 0 \text{ V}$
C_D (Off) ADG1208	6			pF typ	$f = 1 \text{ MHz}$, $V_S = 0 \text{ V}$
	7			pF max	$f = 1 \text{ MHz}$, $V_S = 0 \text{ V}$
C_D (Off) ADG1209	3.5			pF typ	$f = 1 \text{ MHz}$, $V_S = 0 \text{ V}$
	4.5			pF max	$f = 1 \text{ MHz}$, $V_S = 0 \text{ V}$

ADG1208/ADG1209

Parameter	Test Conditions/Comments			
	+25°C	-40°C to +85°C	-40°C to +125°C	Unit
C _D , C _S (On) ADG1208	7 8			pF typ pF max
C _D , C _S (On) ADG1209	5 6			pF typ pF max
POWER REQUIREMENTS				V _{DD} = +16.5 V, V _{SS} = -16.5 V
I _{DD}	0.002		1.0	μA typ μA max
I _{DD}	220		320	μA typ μA max
I _{SS}	0.002		1.0	μA typ μA max
I _{SS}	0.002		1.0	μA typ μA max
V _{DD} /V _{SS}		±5/±16.5	V min/max	V _{DD} = V _{SS}

¹ Temperature range is as follows: Y version: -40°C to +125°C.

² Guaranteed by design, not subject to production test.

SINGLE SUPPLY

$V_{DD} = 12 \text{ V} \pm 10\%$, $V_{SS} = 0 \text{ V}$, GND = 0 V, unless otherwise noted.¹

Table 2.

Parameter	+25°C	-40°C to +85°C	-40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			0 to V_{DD}	V	
On Resistance, R_{ON}	300			Ω typ	$V_S = 0 \text{ V}$ to 10 V, $I_S = -1 \text{ mA}$, see Figure 29
	475	567	625	Ω max	$V_{DD} = 10.8 \text{ V}$, $V_{SS} = 0 \text{ V}$
On Resistance Match Between Channels, ΔR_{ON}	5			Ω typ	$V_S = 0 \text{ V}$ to 10 V, $I_S = -1 \text{ mA}$
On Resistance Flatness, R_{FLAT} (On)	16	26	27	Ω max	
	60			Ω typ	$V_S = 3 \text{ V}$, 6 V, 9 V; $I_S = -1 \text{ mA}$
LEAKAGE CURRENTS					
Source Off Leakage, I_S (Off)	± 0.02			nA typ	$V_{DD} = 13.2 \text{ V}$
	± 0.1	± 0.6	± 1	nA max	$V_S = 1 \text{ V}/10 \text{ V}$, $V_D = 10 \text{ V}/1 \text{ V}$, see Figure 30
Drain Off Leakage, I_D (Off)	± 0.02			nA typ	$V_S = 1 \text{ V}/10 \text{ V}$, $V_D = 10 \text{ V}/1 \text{ V}$, see Figure 30
ADG1208	± 0.1	± 0.6	± 1	nA max	
ADG1209	± 0.1	± 0.6	± 1	nA max	
Channel On Leakage I_D , I_S (On)	± 0.02			nA typ	$V_S = V_D = 1 \text{ V}$ or 10 V; see Figure 31
ADG1208	± 0.2	± 0.6	± 1	nA max	
ADG1209	± 0.2	± 0.6	± 1	nA max	
DIGITAL INPUTS					
Input High Voltage, V_{INH}			2.0	V min	
Input Low Voltage, V_{INL}			0.8	V max	
Input Current, I_{INL} or I_{INH}	± 0.001		± 0.1	μA max	
Digital Input Capacitance, C_{IN}	3			pF typ	$V_{IN} = V_{INL}$ or V_{INH}
DYNAMIC CHARACTERISTICS ²					
Transition Time, $t_{TRANSITION}$	100			ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{ pF}$
	170	210	235		$V_S = 8 \text{ V}$, see Figure 32
t_{ON} (EN)	90			ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{ pF}$
	110	140	160		$V_S = 8 \text{ V}$, see Figure 34
t_{OFF} (EN)	105			ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{ pF}$
	130	155	175		$V_S = 8 \text{ V}$, see Figure 34
Break-Before-Make Time Delay, t_{BBM}	45		20	ns typ	$R_L = 300 \Omega$, $C_L = 35 \text{ pF}$
				ns min	$V_{S1} = V_{S2} = 8 \text{ V}$, see Figure 33
Charge Injection	-0.2			pC typ	$V_S = 6 \text{ V}$, $R_S = 0 \Omega$, $C_L = 1 \text{ nF}$, see Figure 35
Off Isolation	-85			dB typ	$R_L = 50 \Omega$, $C_L = 5 \text{ pF}$, $f = 1 \text{ MHz}$, see Figure 36
Channel-to-Channel Crosstalk	-85			dB typ	$R_L = 50 \Omega$, $C_L = 5 \text{ pF}$, $f = 1 \text{ MHz}$, see Figure 38
-3 dB Bandwidth	450			MHz typ	$R_L = 50 \Omega$, $C_L = 5 \text{ pF}$, see Figure 37
C_S (Off)	1.2			pF typ	$f = 1 \text{ MHz}$, $V_S = 6 \text{ V}$
	1.8			pF max	$f = 1 \text{ MHz}$, $V_S = 6 \text{ V}$
C_D (Off) ADG1208	7.5			pF typ	$f = 1 \text{ MHz}$, $V_S = 6 \text{ V}$
	9			pF max	$f = 1 \text{ MHz}$, $V_S = 6 \text{ V}$
C_D (Off) ADG1209	4.5			pF typ	$f = 1 \text{ MHz}$, $V_S = 6 \text{ V}$
	5.5			pF max	$f = 1 \text{ MHz}$, $V_S = 6 \text{ V}$
C_D , C_S (On) ADG1208	9			pF typ	$f = 1 \text{ MHz}$, $V_S = 6 \text{ V}$
	10.5			pF max	$f = 1 \text{ MHz}$, $V_S = 6 \text{ V}$
C_D , C_S (On) ADG1209	6			pF typ	$f = 1 \text{ MHz}$, $V_S = 6 \text{ V}$
	7.5			pF max	$f = 1 \text{ MHz}$, $V_S = 6 \text{ V}$

ADG1208/ADG1209

Parameter	+25°C	-40°C to +85°C	-40°C to +125°C	Unit	Test Conditions/Comments
POWER REQUIREMENTS					
I _{DD}	0.002		1.0	µA typ µA max	V _{DD} = 13.2 V Digital inputs = 0 V or V _{DD}
I _{DD}	220		330	µA typ µA max	Digital inputs = 5 V
V _{DD}			5/16.5	V min/max	V _{SS} = 0 V, GND = 0 V

¹ Temperature range is as follows: Y version: -40°C to +125°C.

² Guaranteed by design, not subject to production test.

ABSOLUTE MAXIMUM RATINGS

$T_A = 25^\circ\text{C}$, unless otherwise noted.

Table 3.

Parameter	Rating
V_{DD} to V_{SS}	35 V
V_{DD} to GND	-0.3 V to +25 V
V_{SS} to GND	+0.3 V to -25 V
Analog, Digital Inputs ¹	$V_{SS} - 0.3 \text{ V}$ to $V_{DD} + 0.3 \text{ V}$ or 30 mA (whichever occurs first)
Continuous Current, S or D	30 mA
Peak Current, S or D (Pulsed at 1 ms, 10% Duty Cycle max)	100 mA
Operating Temperature Range	
Industrial (Y Version)	-40°C to +125°C
Storage Temperature	-65°C to +150°C
Junction Temperature	150°C
TSSOP, θ_{JA} , Thermal Impedance	112°C/W
LFCSP_VQ, θ_{JA} , Thermal Impedance	30.4°C/W
Reflow Soldering Peak Temperature (Pb-Free)	260(+0/-5)°C

¹ Overvoltages at A, EN, S, or D are clamped by internal diodes. Current should be limited to the maximum ratings given.

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



ADG1208/ADG1209

PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

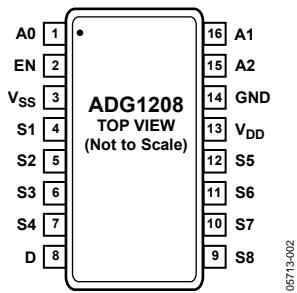


Figure 3. ADG1208 Pin Configuration (TSSOP)

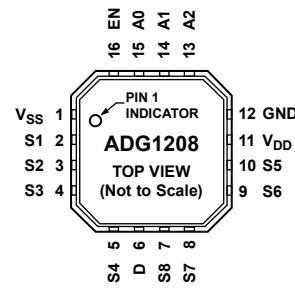


Figure 4. ADG1208 Pin Configuration (LFCSP_VQ), Exposed Pad Tied to Substrate, V_{ss}

Table 4. ADG1208 Pin Function Descriptions

Pin Number		Mnemonic	Description
TSSOP	LFCSP_VQ		
1	15	A0	Logic Control Input.
2	16	EN	Active High Digital Input. When low, the device is disabled and all switches are off. When high, Ax logic inputs determine on switches.
3	1	V_{ss}	Most Negative Power Supply Potential. In single supply applications, it can be connected to ground.
4	2	S1	Source Terminal 1. Can be an input or an output.
5	3	S2	Source Terminal 2. Can be an input or an output.
6	4	S3	Source Terminal 3. Can be an input or an output.
7	5	S4	Source Terminal 4. Can be an input or an output.
8	6	D	Drain Terminal. Can be an input or an output.
9	7	S8	Source Terminal 8. Can be an input or an output.
10	8	S7	Source Terminal 7. Can be an input or an output.
11	9	S6	Source Terminal 6. Can be an input or an output.
12	10	S5	Source Terminal 5. Can be an input or an output.
13	11	V_{dd}	Most Positive Power Supply Potential.
14	12	GND	Ground (0 V) Reference.
15	13	A2	Logic Control Input.
16	14	A1	Logic Control Input.

Table 5. ADG1208 Truth Table

A2	A1	A0	EN	ON SWITCH
X	X	X	0	NONE
0	0	0	1	1
0	0	1	1	2
0	1	0	1	3
0	1	1	1	4
1	0	0	1	5
1	0	1	1	6
1	1	0	1	7
1	1	1	1	8

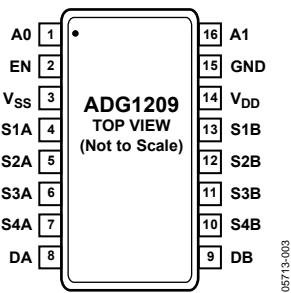


Figure 5. ADG1209 Pin Configuration (TSSOP)

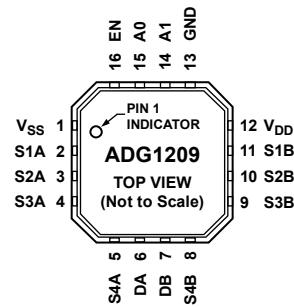
Figure 6. ADG1209 Pin Configurations (LFCSP_VQ), Exposed Pad Tied to Substrate, V_{ss}

Table 6. ADG1209 Pin Function Descriptions

Pin Number	TSSOP	LFCSP_VQ	Mnemonic	Description
1		15	A0	Logic Control Input.
2		16	EN	Active High Digital Input. When low, the device is disabled and all switches are off. When high, Ax logic inputs determine on switches.
3		1	Vss	Most Negative Power Supply Potential. In single supply applications, it can be connected to ground.
4		2	S1A	Source Terminal 1A. Can be an input or an output.
5		3	S2A	Source Terminal 2A. Can be an input or an output.
6		4	S3A	Source Terminal 3A. Can be an input or an output.
7		5	S4A	Source Terminal 4A. Can be an input or an output.
8		6	DA	Drain Terminal A. Can be an input or an output.
9		7	DB	Drain Terminal B. Can be an input or an output.
10		8	S4B	Source Terminal 4B. Can be an input or an output.
11		9	S3B	Source Terminal 3B. Can be an input or an output.
12		10	S2B	Source Terminal 2B. Can be an input or an output.
13		11	S1B	Source Terminal 1B. Can be an input or an output.
14		12	Vdd	Most Positive Power Supply Potential.
15		13	GND	Ground (0 V) Reference.
16		14	A1	Logic Control Input.

Table 7. ADG1209 Truth Table

A1	A0	EN	ON SWITCH PAIR
X	X	0	NONE
0	0	1	1
0	1	1	2
1	0	1	3
1	1	1	4

ADG1208/ADG1209

TYPICAL PERFORMANCE CHARACTERISTICS

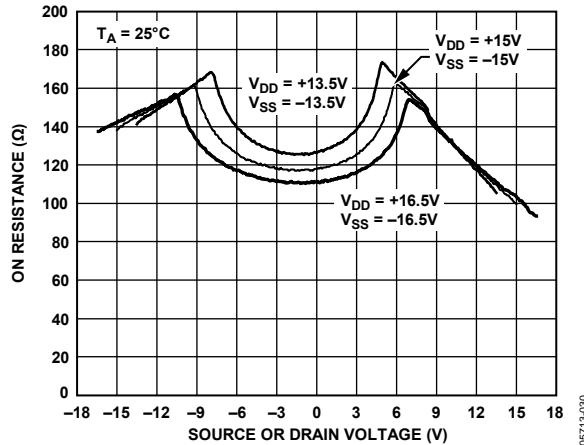


Figure 7. On Resistance as a Function of V_D (V_S) for Dual Supply

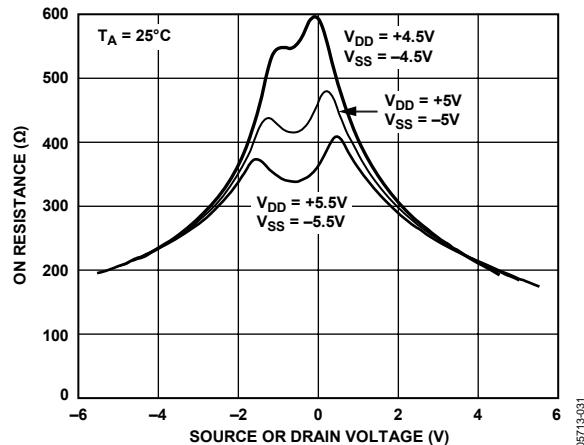


Figure 8. On Resistance as a Function of V_D (V_S) for Dual Supply

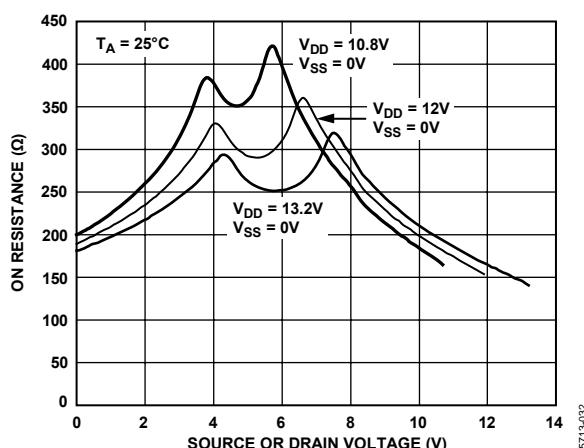


Figure 9. On Resistance as a Function of V_D (V_S) for Single Supply

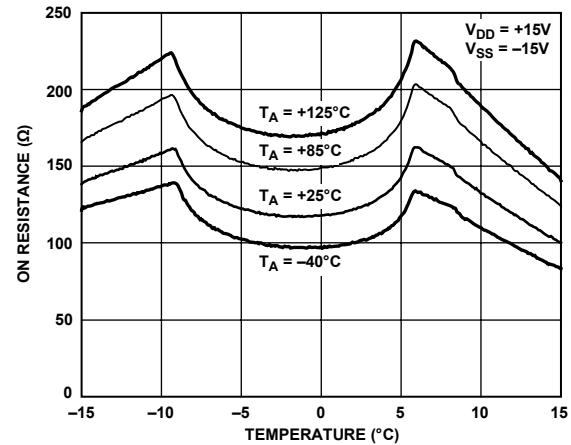


Figure 10. On Resistance as a Function of V_D (V_S) for Different Temperatures, Dual Supply

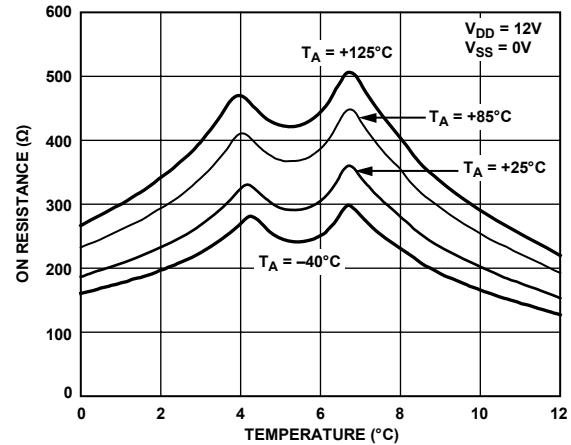


Figure 11. On Resistance as a Function of V_D (V_S) for Different Temperatures, Single Supply

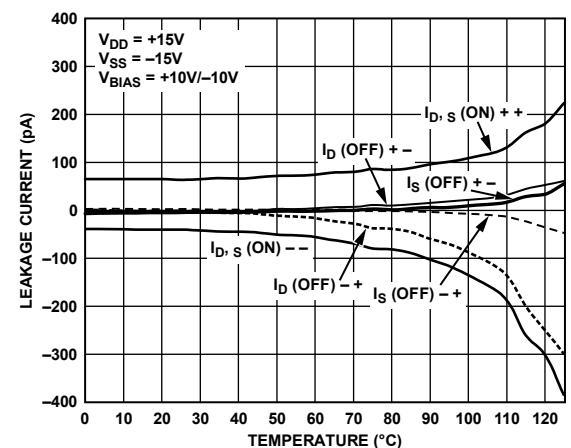


Figure 12. ADG1208 Leakage Currents as a Function of Temperature, Dual Supply

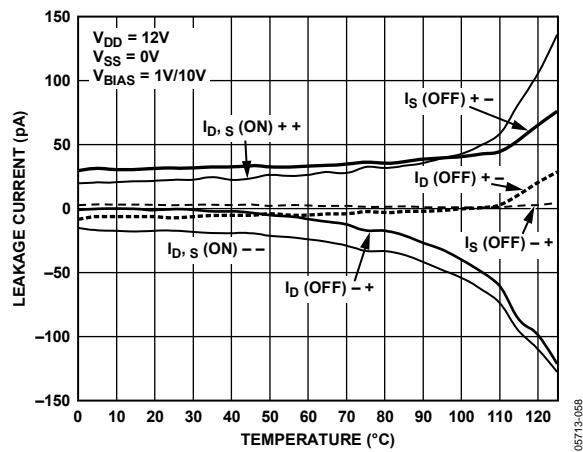


Figure 13. ADG1208 Leakage Currents as a Function of Temperature, Single Supply

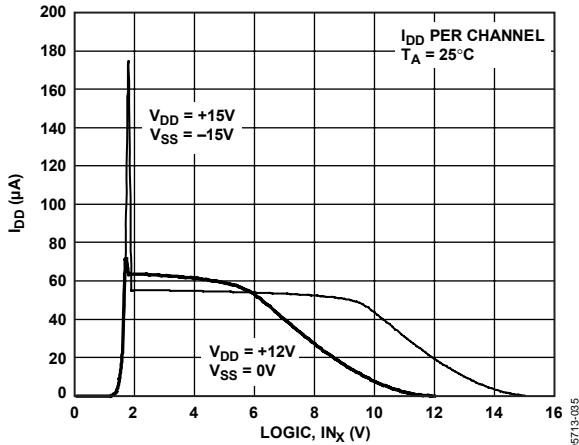


Figure 14. I_{DD} vs. Logic Level

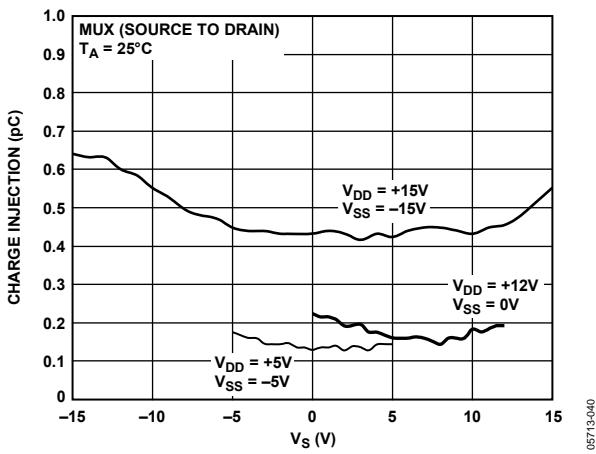


Figure 15. Source-to-Drain Charge Injection vs. Source Voltage

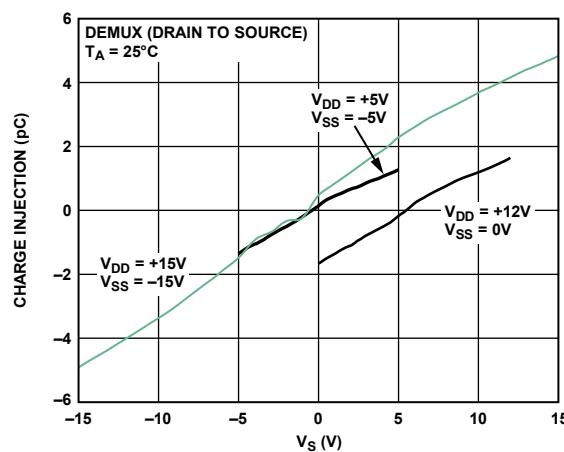


Figure 16. Drain-to-Source Charge Injection vs. Source Voltage

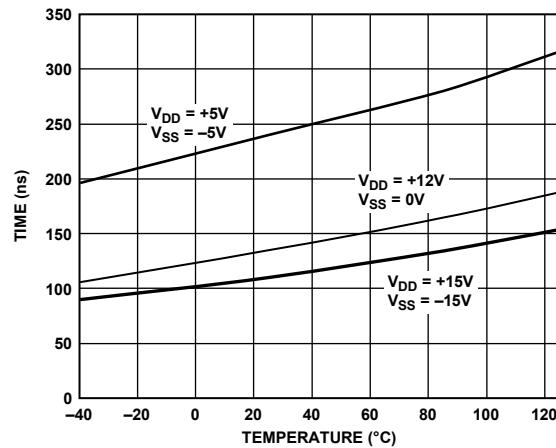


Figure 17. t_{ON}/t_{OFF} Times vs. Temperature

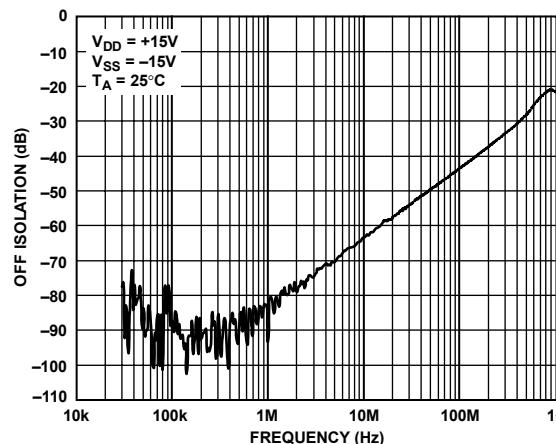


Figure 18. Off Isolation vs. Frequency

ADG1208/ADG1209

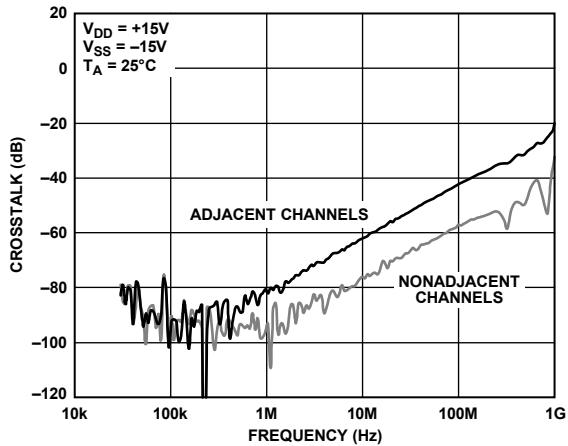


Figure 19. ADG1208 Crosstalk vs. Frequency

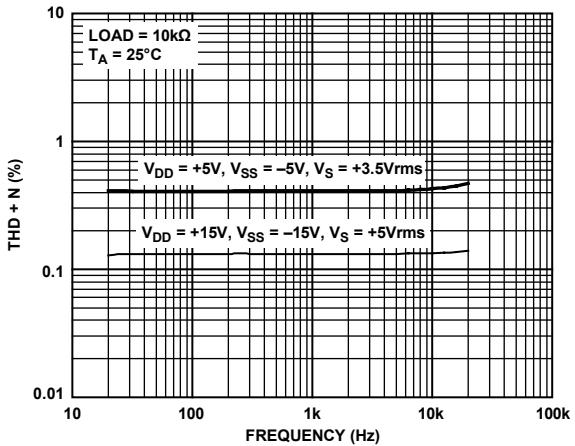


Figure 22. THD + N vs. Frequency

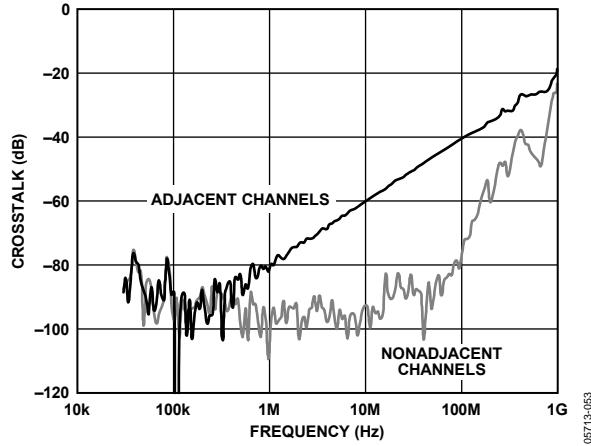


Figure 20. ADG1209 Crosstalk vs. Frequency

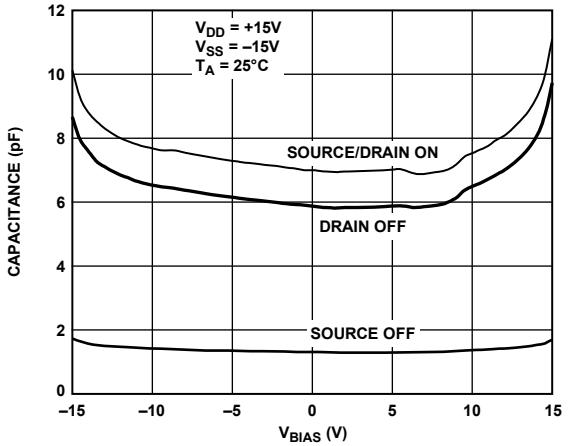


Figure 23. ADG1208 Capacitance vs. Source Voltage,
±15 V Dual Supply

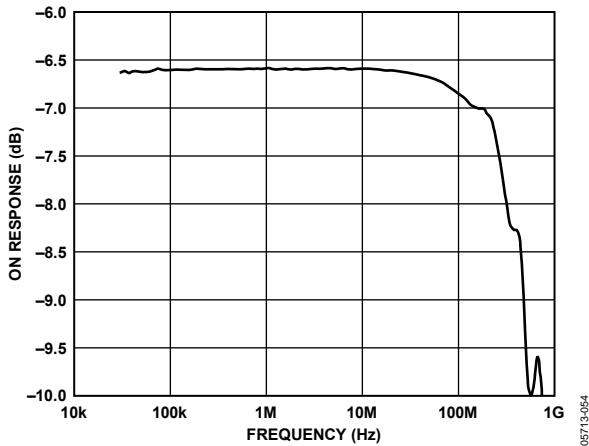


Figure 21. On Response vs. Frequency

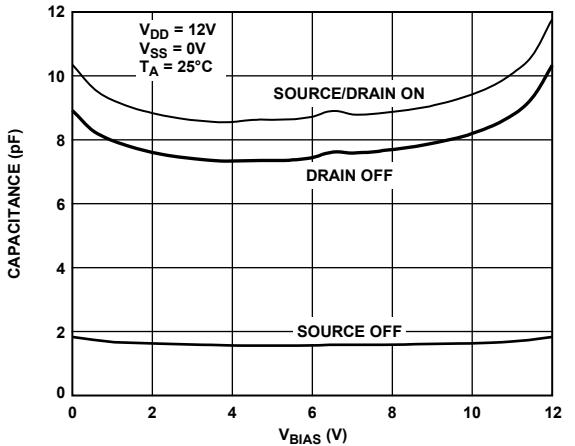


Figure 24. ADG1208 Capacitance vs. Source Voltage,
12 V Single Supply

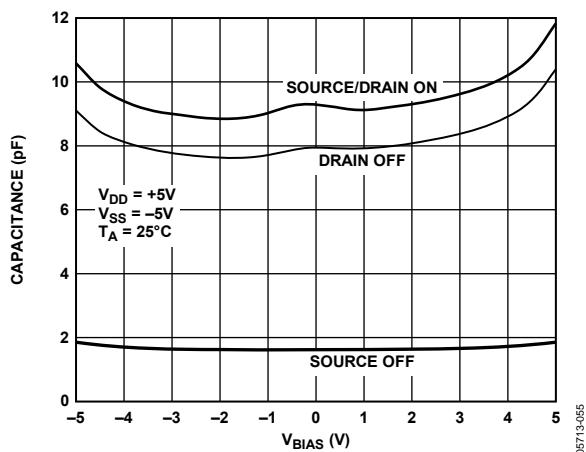


Figure 25. ADG1208 Capacitance vs. Source Voltage, $\pm 5\text{ V}$ Dual Supply

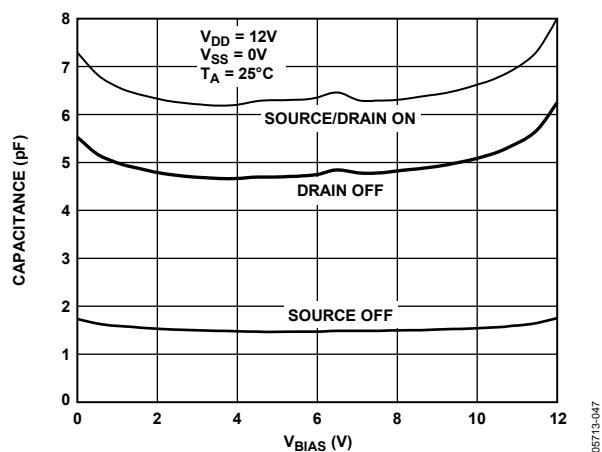


Figure 27. ADG1209 Capacitance vs. Source Voltage, 12 V Single Supply

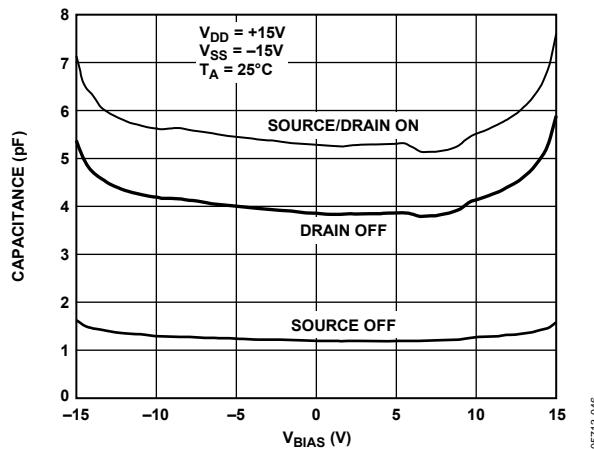


Figure 26. ADG1209 Capacitance vs. Source Voltage, $\pm 15\text{ V}$ Dual Supply

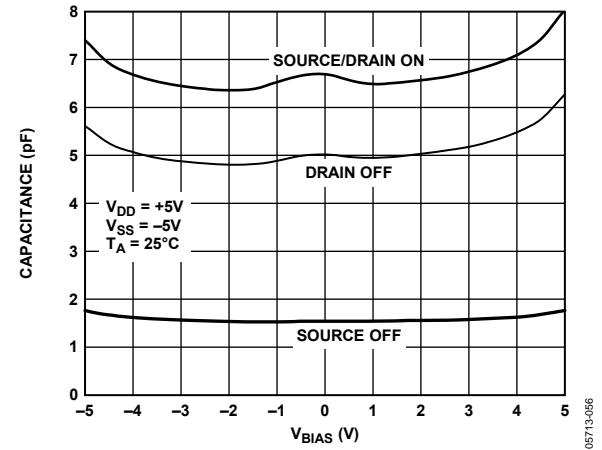


Figure 28. ADG1209 Capacitance vs. Source Voltage, $\pm 5\text{ V}$ Dual Supply

TERMINOLOGY

R_{ON}		t_{TRANSITION}	
Ohmic resistance between D and S.		Delay time between the 50% and 90% points of the digital inputs and the switch on condition when switching from one address state to another.	
ΔR_{ON}		T_{BBM}	
Difference between the R _{ON} of any two channels.		Off time measured between the 80% point of both switches when switching from one address state to another.	
I_S (Off)		V_{INL}	
Source leakage current when the switch is off.		Maximum input voltage for Logic 0.	
I_D (Off)		V_{INH}	
Drain leakage current when the switch is off.		Minimum input voltage for Logic 1.	
I_D, I_S (On)		I_{INL} (I_{INH})	
Channel leakage current when the switch is on.		Input current of the digital input.	
V_D (V_S)		I_{DD}	
Analog voltage on terminals D, S.		Positive supply current.	
C_S (Off)		I_{SS}	
Channel input capacitance for off condition.		Negative supply current.	
C_D (Off)		Off Isolation	
Channel output capacitance for off condition.		A measure of unwanted signal coupling through an off channel.	
C_D, C_S (On)		Charge Injection	
On switch capacitance.		A measure of the glitch impulse transferred from the digital input to the analog output during switching.	
C_{IN}		Bandwidth	
Digital input capacitance.		The frequency at which the output is attenuated by 3 dB.	
t_{ON} (EN)		On Response	
Delay time between the 50% and 90% points of the digital input and switch on condition.		The frequency response of the on switch.	
t_{OFF} (EN)		THD + N	
Delay time between the 50% and 90% points of the digital input and switch off condition.		The ratio of the harmonic amplitude plus noise of the signal to the fundamental.	

TEST CIRCUITS

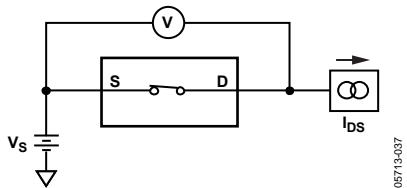


Figure 29. On Resistance

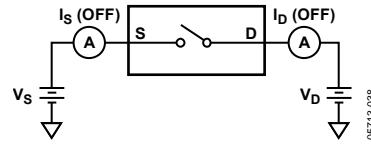


Figure 30. Off Leakage

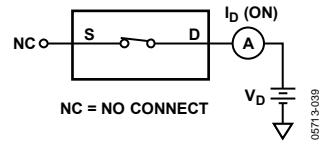
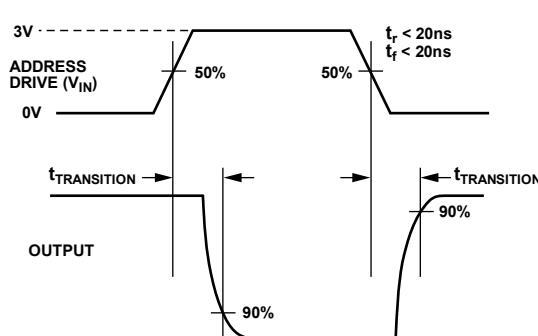
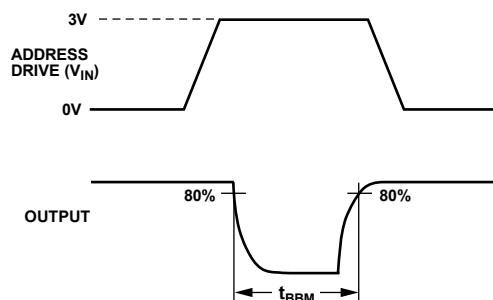
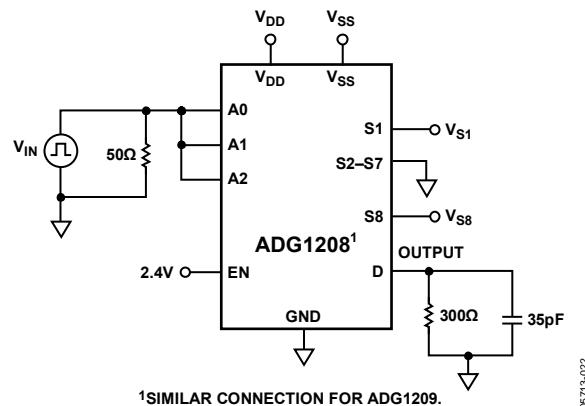
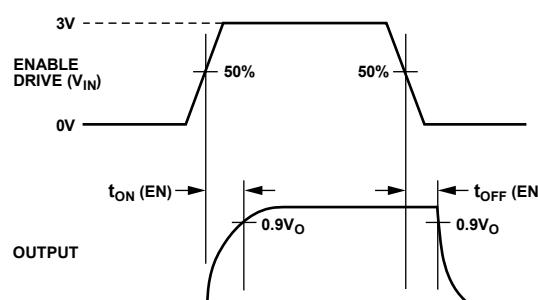
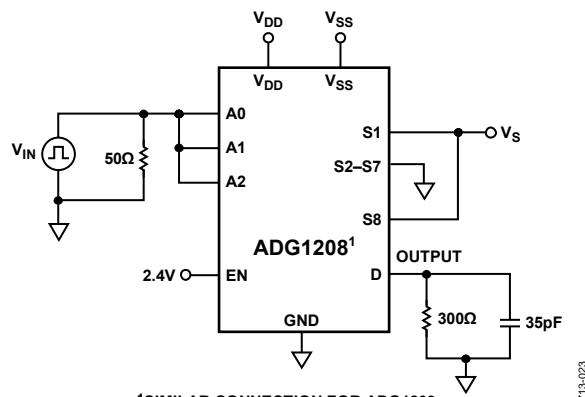
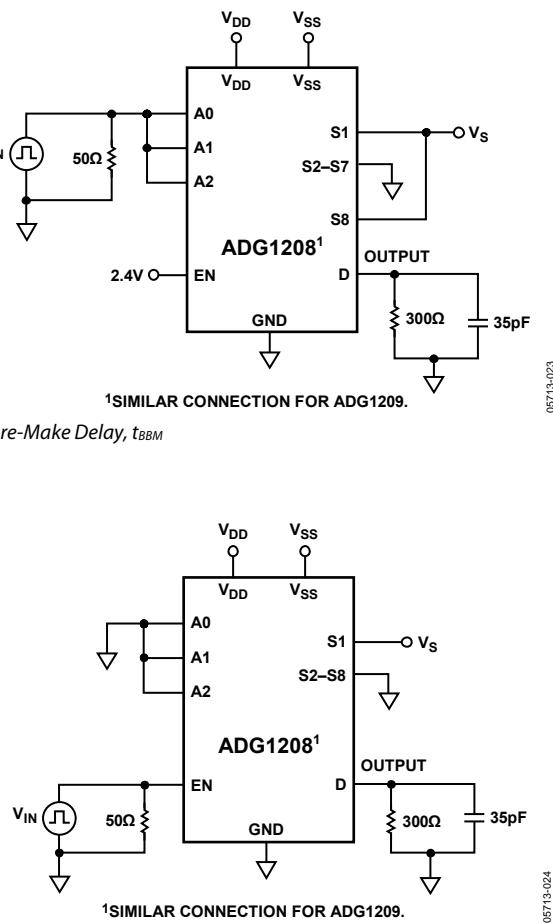


Figure 31. On Leakage

Figure 32. Address to Output Switching Times, $t_{TRANSITION}$ Figure 33. Break-Before-Make Delay, t_{BBM} Figure 34. Enable Delay, t_{ON} (EN), t_{OFF} (EN)

ADG1208/ADG1209

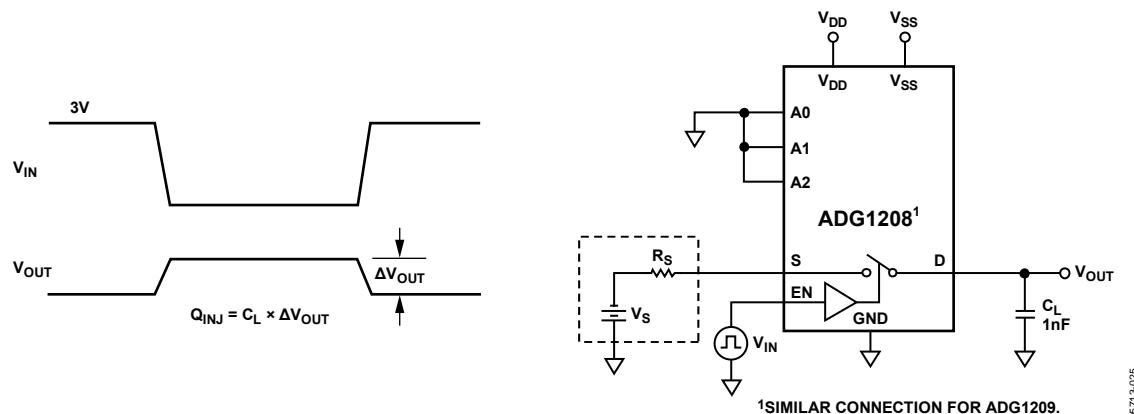


Figure 35. Charge Injection

05713-025

¹SIMILAR CONNECTION FOR ADG1209.

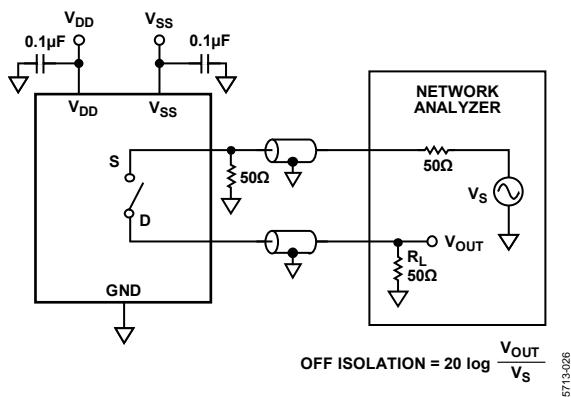


Figure 36. Off Isolation

05713-026

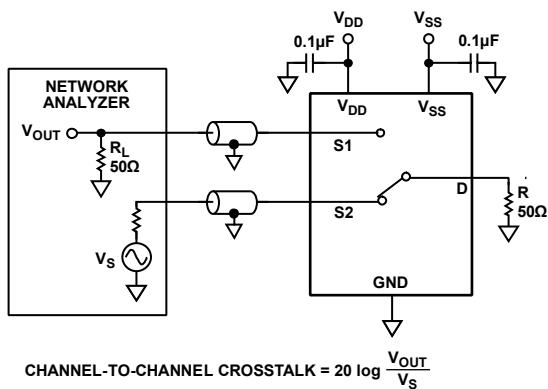


Figure 38. Channel-to-Channel Crosstalk

05713-028

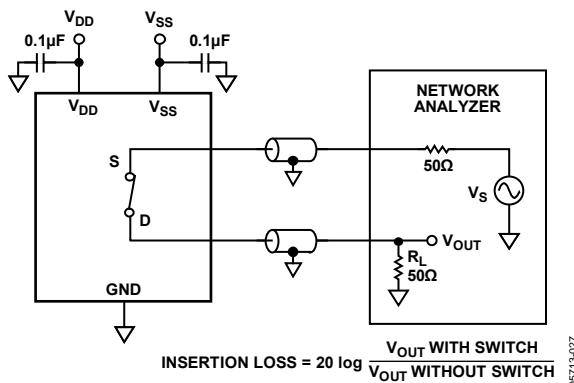


Figure 37. Bandwidth

05713-027

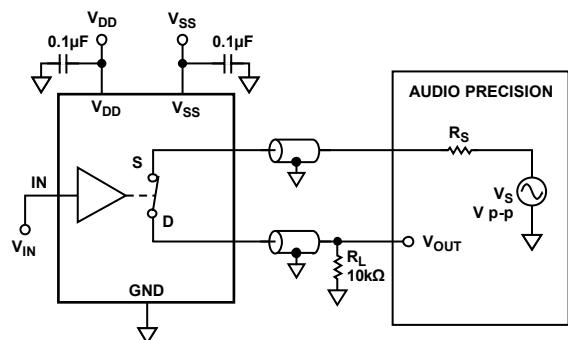


Figure 39. THD + Noise

05713-029

OUTLINE DIMENSIONS

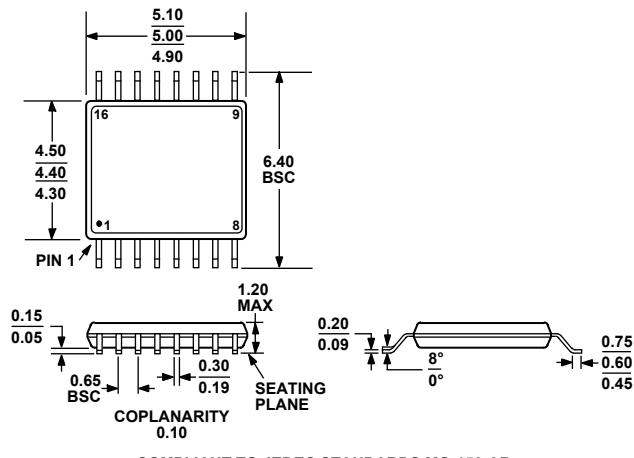


Figure 40. 16-Lead Thin Shrink Small Outline Package [TSSOP]
(RU-16)

Dimensions shown in millimeters

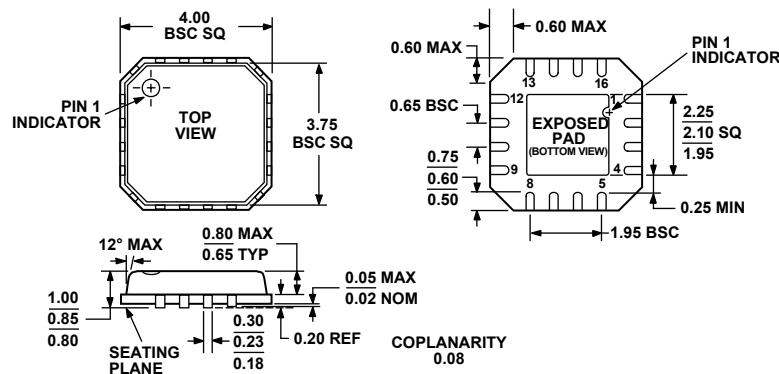


Figure 41. 16-Lead Lead Frame Chip Scale Package [LFCSP_VQ]
4 mm × 4 mm Body, Very Thin Quad
(CP-16-4)

Dimensions shown in millimeters

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
ADG1208YRUZ ¹	-40°C to +125°C	16-Lead Thin Shrink Small Outline Package [TSSOP]	RU-16
ADG1208YRUZ-REEL7 ¹	-40°C to +125°C	16-Lead Thin Shrink Small Outline Package [TSSOP]	RU-16
ADG1208YCPZ-REEL ¹	-40°C to +125°C	16-Lead Lead Frame Chip Scale Package [LFCSP_VQ]	CP-16-4
ADG1208YCPZ-REEL7 ¹	-40°C to +125°C	16-Lead Lead Frame Chip Scale Package [LFCSP_VQ]	CP-16-4
ADG1209YRUZ ¹	-40°C to +125°C	16-Lead Thin Shrink Small Outline Package [TSSOP]	RU-16
ADG1209YRUZ-REEL7 ¹	-40°C to +125°C	16-Lead Thin Shrink Small Outline Package [TSSOP]	RU-16
ADG1209YCPZ-REEL ¹	-40°C to +125°C	16-Lead Lead Frame Chip Scale Package [LFCSP_VQ]	CP-16-4
ADG1209YCPZ-REEL7 ¹	-40°C to +125°C	16-Lead Lead Frame Chip Scale Package [LFCSP_VQ]	CP-16-4

¹ Z = Pb-free part.

ADG1208/ADG1209

NOTES

NOTES

ADG1208/ADG1209

NOTES